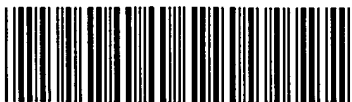


Search Notes

Application/Control No.

10/660,517

Examiner

Alan S. Chen

Applicant(s)/Patent under
Reexamination

CHANG, SHU-MEI

Art Unit

2182

SEARCHED

Class	Subclass	Date	Examiner
710	12	4/28/2005	ASC
↓	18	↓	↓
↓	19	↓	↓
↓	63	↓	↓
↓	64	↓	↓
↓	72	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT	4/28/2005	ASC